Correlation

- Observation (poly section 9.1 topology correlation)
- Sensor placement objectives and pathologies
- Correlation criteria (section 9.2 and 9.3)
- Expansion (section 9.5)





MS2SC PROVIR http://savoir.ensam.eu/moodle/course/view.php?id=1874 http://savoir.ensam.eu/moodle/course/view.php?id=490

Hybrid test & FEM



Identification error

- Noisy measurements
- Identification bias
- NL, time varying, ...





FEM error •Geometry •Material parameters



Updating = estimate parameters using correlation objective Expansion = estimate all DOF knowing test and model State estimation, hybrid twin

Basic topology correlation process

CoTopo - feplot(6,'cax1')			– U ×
-ile Feplot Edit View De	ebug Desktop Window Help	💡 🛱 🔟 🌿 📾 📾	
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		auroat chiest info	

Topology correlation process

- Initial orient (coarse)
- Give reference points & reposition

- Optimize orientation to minimize distance
- Analyze errors











Topology Correlation problems

- Determine matching surface
- Geometry mismatch
- Handle offsets for shells
- Exact location in presence of camera distortion





View & correlate

- Connect to allow viewing
- Use regularity to avoid distortion
- Use exact topology



Avoid distortions : triax or not

- Non triaxial measurements can induce perceived deformation
- Wire-frame as truss and expand

Expansion \Leftrightarrow efficient use of channel count







Correlation criteria

- FRF comparison (section 9.6)
- Sensor based : frequencies, MAC, relative error, MACCo (9.2)
- Model based : orthogonality, dynamic residual (9.3)
 Needed tools
- Topology correlation / observation
- Modeshape expansion / estimation

FRF comparison

$[H(s)] = [I + L_L(s)] [H_M(s) + H_R(s)] [I + L_R(s)]$



Frequency comparison : needs pairing



MAC and others

- Discuss MAC on blackboard (section 9.2.2)
- Show full and reduced versions (this requires talking about reduction)
- Relation with orthogonality conditions
- Relative error with or without scaling

Modal Assurance Criterion



Basic shape correlation

CoShape - Figure 1: MacPro

File Edit View Insert Tools Debug Desktop Window Help II_MAC

X

+1 Figure 1: MacPro X MAC(1) X MAC-Error(1) X feplot(2,'cax1') Normal modes X ErrMac X MAC X Qual X Mode 1 at 0 Hz
MAC Z Qual Z Mode 1 at 0 Hz
Data IdMain NsensNact=1011 Nshape=22 IdMain NsensNact=1011 Nshape=22 IdMain NsensNact=1011 Nshape=20 Immodel Nsens=1011 NDof=63678 Immodel Immodel <
sela {'-Test','ShowFITestDef'}
selb {'-linface', 'ShowFIMDef'}
MacPlot MAC Cross A-B
GroupA [8 9] [11 12] 1 @ 441.5 Hz 0.24 %
GroupB [14 15] [17 18]
Combine 0
HacError ErrB
⊕-SensorSet
B-SaveDock Save

https://voutu.be/tVV-R2r-3M8

Correlation : mode crossing & MAC combine

- High sensitivity for close modes associated with mode crossing
- MAC can drop to 0.5
- MAC combine linear combination of close modes = stays at 1.
- Orthonormal combination of modes in a group

$$A = argmin \| [\phi_{test}]_{gA} - [c\phi_{FEM}]_{gB}[A] \|$$



MAC & sensors : historical methods

- MAC on sensor sets
 ② Localize area of poor correlation
 ③ No automated set definition
- COMAC : is a specific sensor bad ?
 - correlation of multiple modes at one sensor
 - eCOMAC : allow incorrect modeshape scaling
 - Not per mode / sensor
- MACCO : does correlation improve with less sensors ?
 - © Easy to implement
 - $\ensuremath{\textcircled{\odot}}$ Sensor sets per mode or global
 - $\ensuremath{\textcircled{\odot}}$ No understanding of why each sensor is removed.



[1] N. A. J. Lieven, D. J. Ewins, « Spatial Correlation of Modeshapes, The Coordinate Modal Assurance Criterion (COMAC) », IMAC, 1988.

[2] Brughmans, Leuridan, Blauwkamp, « The application of FEM-EMA correlation and validation techniques on a body-in-white », IMAC, 1993

[3] Martin, Balmes, Chancelier, « Characterization of identification errors and uses in localization of poor modal correlation », MSSP, vol. 88, p. 62-80, may 2017

MACCo algorithm



Test/identification error



14,19

13,8%

13,7%

13,6%

6,9%

2,1%

4,1%

2,4%

35,5%

27,8%

19,4%

74,2%

,03

,03

,03

,03

1244,03

6 1283,03

6

6 1153,03

6 1395,03 1,0%

0,3%

0,6% 0,3%

Per mode/sensor error/noise & contribution

MAC & sensors : MACCo variants

MACErr : Ignore sensors with bad identification

- MACCo : sort sensors by impact on MAC Removed sensors may indicate
- Bad measurements
- Model errors





Each sensor removed improves MAC by 2%



MAC : sensor placement







HITACHI Inspire the Next

Expansion in structural dynamics : a perspective gained from success and errors in test/FEM twin building

Etienne BALMES (ENSAM PIMM & SDTools) G. MARTIN, G. Vermot des Roches (SDTools) T. CHANCELIER, S. THOUVIOT, Hitachi

CSMA, Giens, May 18, 2022

https://hal.archives-ouvertes.fr/hal-03717617v1

Learning experimental shapes in squeal event







Variability - influence of wheel angle Reproductibility - Multiple events



Braking event 1

Braking event 2



Complex ODS from 3D-SLDV

- 431 points
- f = 4050 Hz

Observation / test error



Equilibrium / model error / ignorance

 $[M]{\ddot{q}} + [C]{q} + [K(p_{Est})]{q} = F_{ext} + R_L(p, noise) \text{ in time} = \text{Kalman}$ $[Ms^2 + Cs + K(p_{Est})]{q(s)} = F_{ext} + R_L(p, noise) \text{ in frequency expansion}$



Measure residuals $||\{R_L\}||_{K}$ 1. Work $\{R_D\} = [K]^{-1}\{I$ 2. Energy $\epsilon_{Mod} = ||\{R_L\}||_{K}^2 = R_D^T K$ 3. Relative error $\epsilon_{Mod}^R = \frac{\epsilon_{Mod}}{||\{q_{Exp}\}||_{K}^2}$ $\epsilon_{Mod}^R = 0\%$ $\epsilon_{Mod}^R = 3\%$

Complex mode

Our target

 $\epsilon_{Mod}^{R} = 82\%$

Dynamic expansion

Model based estimation / expansion / hybrid twin



Outline

- 1. Coefficient γ to balance between the two errors
- 2. States, reduction & numerical cost
- 3. Ouput-error norm Q
- 4. Analyze model error K-norm

1. Test / model tradeoff

Modeling and test error minimization : multi-objective cost function

$$J(q_{Exp}, \gamma) = \epsilon_{Mod} + \gamma \epsilon_{Test}$$

 γ too low : no motion (no external input)





1. Test / model tradeoff

Modeling and test error minimization : multi-objective cost function

$$J(q_{Exp}, \gamma) = \epsilon_{Mod} + \gamma \epsilon_{Test}$$

 γ too low : no motion γ increase : expanded shape gets closer to the measurement







1. Test / model tradeoff

Modeling and test error minimization : multi-objective cost function

$$J(q_{Exp}, \gamma) = \epsilon_{Mod} + \gamma \epsilon_{Test}$$

 γ too low : no motion γ increase : expanded shape gets closer to the measurement γ too high : model error concentration at sensors







1. Test / model tradeoff : conclusion

$$J(q_{Exp}, \gamma) = \epsilon_{Mod} + \gamma \epsilon_{Test}$$

 γ too low : no motion γ too high : model error concentration at sensors

Good value : ϵ_{Test} low enough, ϵ_{Mod} smooth





ErrTest low « enough » « Smooth » ErrMod



Necessities

- at least 20 values 4 orders of magnitude
- Interactive γ navigation
- Error viewing interfaces
- Relative error give local minimima & optima ≠ weighted error

2. States, reduction, numerical cost

Multi-objective problem $J(q_{Exp}, \gamma) = \epsilon_{Mod} + \gamma \epsilon_{Test}$ Rewritten as extended saddle point $\begin{bmatrix} \hat{K} & -Z(\omega, p) \\ -Z(\omega, p) & \gamma[c]^T Q[c] \end{bmatrix} \begin{Bmatrix} R_D \\ q_{Ex} \end{Bmatrix} = \begin{Bmatrix} 0 \\ \gamma[c]^T Q y_{test} \end{Bmatrix}$

Two levels of variable separation

- FEM $u(x,t) = N(x)q_i(t)$
- Modal analysis (Ritz) $\{q_i(t,p)\} = [T]\{q_R(t,p)\}$

[T] chosen for bandwith, loads (external, parametric)



- Modes $\{\phi_j(p_0)\}$
- Loads at sensors $[c]^T$
- Parametric loads $\left[\frac{\partial Z}{\partial p}\right]\left\{\phi_{j}(p)\right\}$



Environment Design paint



100 shapes 5*100 shapes 1239 shapes

2. States, reduction, numerical cost

Ritz reduction

- Learning $\{\phi_j(p_1)\} \{\phi_j(p_2)\} [K]^{-1} [\partial Z/\partial p] \{\phi_j(p)\} [c]^T$
- Basis building :
 - Full 1.7e6 DOF x (100 + 500 + 1239) vectors = 23 GB
 - Full global modes (SVD/Eig)
 - Sparse sensor shape $[K]^{-1}[c]^T$ (LU) 7 MB
 - Other basis building at SDTools
 - Full parametric shapes (could be sparse)
 - Component modes block-wise & two level reduction (PhD Vermot, 2011)







2. States, reduction, numerical cost

Ritz reduction (offline $\propto 1$ h, once)

Expansion $\begin{bmatrix} \widehat{K} & -Z(\omega, p) \\ -Z(\omega, p) & \gamma[c]^T Q[c] \end{bmatrix} \begin{Bmatrix} R_D \\ q_{Ex} \end{Bmatrix} = \begin{Bmatrix} 0 \\ \gamma[c]^T Q y_{test} \end{Bmatrix}$

- Full NEVER
- Reduced $\propto 1s$, 1e3 times
 - Analytic gradient if updating
- Restitution : online / interactive
 - Display **<1ms**, energy per element **<1s**
 - Online saves memory 1000 shapes : full 25 GB, reduced 28 MB



Environment Design paint

In

System

States

Out

3. Test error norm



4. Model error analysis

$$\operatorname{In} \begin{bmatrix} \widehat{K} & -Z(\omega, p) \\ -Z(\omega, p) & \gamma[c]^T Q[c] \end{bmatrix} \begin{Bmatrix} R_D \\ q_{Ex} \end{Bmatrix} = \begin{Bmatrix} 0 \\ \gamma[c]^T Q y_{test} \end{Bmatrix}$$

One has $[Z(\omega, p)]{R_D} = [c]^T \gamma (cq_{Ex} - y_{Test})$

 The model error is approximated as dynamic response to point loads at sensors
 => stress concentrations

But sensor enrichment can be
split by regularity/frequency
$$[T] = [\phi_M \ T_{sens}^{\perp}]$$

$$\varepsilon_{Mod} = \{R_D\}|_M^T \begin{bmatrix} \ddots & & \\ & \omega_M^2 & \\ & & \ddots \end{bmatrix} \{R_D\}|_M + \{R_D\}|_{\perp}^T \begin{bmatrix} \ddots & & \\ & \omega_{\perp}^2 & \\ & & \ddots \end{bmatrix} \{R_D\}|_{\perp}$$



4. Model error analysis

- Regularity may still not be sufficient
- Bottois (PhD 2019) used Bayesian inference
- MDRE expansion used to estimate shape q^{Exp}
- $\begin{cases} \boldsymbol{\mu}_{\boldsymbol{\delta}_{1}} = \tilde{E}_{t}\mathbf{K}_{t}\mathbf{y} + \tilde{E}_{f}\mathbf{K}_{f}\mathbf{y} \\ \boldsymbol{\Sigma}_{\boldsymbol{\delta}_{1}} = (\tilde{E}_{t}\mathbf{K}_{t} + \tilde{E}_{f}\mathbf{K}_{f})\sigma_{n}^{2}\boldsymbol{\Sigma}_{n}(\tilde{E}_{t}\mathbf{K}_{t} + \tilde{E}_{f}\mathbf{K}_{f})^{H} \\ \boldsymbol{\mu}_{\boldsymbol{\delta}_{2}} = \omega^{2}\mathbf{M}\mathbf{y} \\ \boldsymbol{\Sigma}_{\boldsymbol{\delta}_{2}} = (\omega^{2}\mathbf{M})\sigma_{n}^{2}\boldsymbol{\Sigma}_{n}(\omega^{2}\mathbf{M})^{H} \\ & \begin{cases} \boldsymbol{\Sigma}_{\boldsymbol{\delta}} = \left(\boldsymbol{\Sigma}_{\boldsymbol{\delta}_{1}}^{-1} + \boldsymbol{\Sigma}_{\boldsymbol{\delta}_{2}}^{-1}\right)^{-1} \\ \boldsymbol{\mu}_{\boldsymbol{\delta}} = \boldsymbol{\Sigma}_{\boldsymbol{\delta}}\left(\boldsymbol{\Sigma}_{\boldsymbol{\delta}_{1}}^{-1}\boldsymbol{\mu}_{\boldsymbol{\delta}_{1}} + \boldsymbol{\Sigma}_{\boldsymbol{\delta}_{2}}^{-1}\boldsymbol{\mu}_{\boldsymbol{\delta}_{2}}\right) \end{cases} \end{cases}$
- Good for displacement but not stress. Keep on edge where unknown force R_I occurs and to estimate acceleration field
- Estimate regularized interior displacement q_{C}^{Reg} (possible shift α)
- For true solution $q_{C}^{Exp} = q_{C}^{Reg}$

$$[M(s^{2}-\alpha)] \begin{Bmatrix} q_{I}^{Exp} \\ q_{C}^{Exp} \end{Bmatrix} + (M\alpha + K(p)) \begin{Bmatrix} q_{I}^{Exp} \\ q_{C}^{Reg} \end{Bmatrix} = \begin{Bmatrix} R_{I} \\ \mathbf{0} \end{Bmatrix}$$



Conclusion

- Understanding multi-objective 1e3 points needed
- Reduction is critical
 - Ritz reduction (offline \propto 1h, once)
 - Learning $\{\phi_j(p_1)\} \{\phi_j(p_2)\} [K]^{-1}[c]^T$
 - Basis building : SVD/EIG/LU
- Ongoing work
 - Parameter updating
 - Quantification of test errors
 - Non-linear transient
 - GUI / user friendliness



Thanks to (alphabetical order) : Airbus, Arianespace, Bosch, ... Daimler, EDF, ESA, JE Electric, PSA/Stellantis, ...



Static/dynamic expansion



- Static expansion has cut-off frequency
- Measurement errors are not accounted for

Fixed sensor mode



Uses

- Analyze static expansion validity
- Place additional sensors to extend frequency band (IMAC 05)